# Kazuo Ishizuka

List of Publications by Year
in descending order

Source: https://exaly.com/author-pdf/11116520/publications.pdf

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| | | 394421 | 501196 |
|---|---|---|---|
| 35 | 1,873 | 19 | 28 |
| papers | citations | h-index | g-index |

| | | | |
|---|---|---|---|
| 36 | 36 | 36 | 1825 |
| all docs | docs citations | times ranked | citing authors |

| # | Article | IF | Citations |
|---|---|---|---|
| 1 | Element-selective imaging of atomic columns in a crystal using STEM and EELS. Nature, 2007, 450, 702-704. | 27.8 | 359 |
| 2 | Contrast transfer of crystal images in TEM. Ultramicroscopy, 1980, 5, 55-65. | 1.9 | 269 |
| 3 | A practical approach for STEM image simulation based on the FFT multislice method. Ultramicroscopy, 2002, 90, 71-83. | 1.9 | 264 |
| 4 | Phase measurement of atomic resolution image using transport of intensity equation. Microscopy (Oxford, England), 2005, 54, 191-197. | 1.5 | 152 |
| 5 | Direct observation of single dopant atom in light-emitting phosphor of Î²-SiAlON:Eu2+. Applied Physics Letters, 2009, 94, . | 3.3 | 147 |
| 6 | Local crystal structure analysis with several picometer precision using scanning transmission electron microscopy. Ultramicroscopy, 2010, 110, 778-782. | 1.9 | 105 |
| 7 | Direct observation and dynamics of spontaneous skyrmion-like magnetic domains in a ferromagnet. Nature Nanotechnology, 2013, 8, 325-328. | 31.5 | 64 |
| 8 | Threeâ€dimensional reconstruction of magnetic vector fields using electronâ€holographic interferometry. Journal of Applied Physics, 1994, 75, 4593-4598. | 2.5 | 63 |
| 9 | Prospects of atomic resolution imaging with an aberration-corrected STEM. Journal of Electron Microscopy, 2001, 50, 291-305. | 0.9 | 51 |
| 10 | Local crystal structure analysis with 10-pm accuracy using scanning transmission electron microscopy. Journal of Electron Microscopy, 2009, 58, 131-136. | 0.9 | 49 |
| 11 | Three-dimensional reconstruction of electric-potential distribution in electron-holographic interferometry. Applied Optics, 1994, 33, 829. | 2.1 | 47 |
| 12 | Analysis of electron image detection efficiency of slow-scan CCD cameras. Ultramicroscopy, 1993, 52, 7-20. | 1.9 | 46 |
| 13 | Managing dose-, damage- and data-rates in multi-frame spectrum-imaging. Microscopy (Oxford,) Tj ETQq1 1 0.784314 rgBT /Overlock | 1.5 | 42 |
| 14 | The study of Al-L23 ELNES with resolution-enhancement software and first-principles calculation. Journal of Electron Microscopy, 2003, 52, 299-303. | 0.9 | 35 |
| 15 | Spatially resolved diffractometry with atomic-column resolution. Ultramicroscopy, 2011, 111, 1111-1116. | 1.9 | 32 |
| 16 | Decisive factors for realizing atomic-column resolution using STEM and EELS. Micron, 2008, 39, 257-262. | 2.2 | 26 |
| 17 | 0.23eV energy resolution obtained using a cold field-emission gun and a streak imaging technique. Micron, 2005, 36, 465-469. | 2.2 | 24 |
| 18 | Quantitative annular dark-field imaging of single-layer grapheneâ€”II: atomic-resolution image contrast. Microscopy (Oxford, England), 2015, 64, 409-418. | 1.5 | 23 |

| # | Article | IF | Citations |
|---|---|---|---|
| 19 | Quantitative annular dark-field imaging of single-layer graphene. Microscopy (Oxford, England), 2015, 64, 143-150. | 1.5 | 20 |
| 20 | Quantitative evaluation of temporal partial coherence using 3D Fourier transforms of through-focus TEM images. Ultramicroscopy, 2013, 134, 86-93. | 1.9 | 15 |
| 21 | Decisive factors for realizing atomic-column resolution using STEM and EELS. Micron, 2008, 39, 653-657. | 2.2 | 10 |
| 22 | Extremely low count detection for EELS spectrum imaging by reducing CCD read-out noise. Ultramicroscopy, 2019, 207, 112827. | 1.9 | 9 |
| 23 | Rapid measurement of low-order aberrations using Fourier transforms of crystalline Ronchigrams. Ultramicroscopy, 2017, 180, 59-65. | 1.9 | 5 |
| 24 | Phase-extraction technique for electron holography using a grating optical system. Applied Optics, 1992, 31, 5940. | 2.1 | 4 |
| 25 | Resolution improvement by titled single-sideband holography: preliminary experiments. Ultramicroscopy, 1994, 53, 9-14. | 1.9 | 4 |
| 26 | Why Do We Need to Use Three-Dimensional (3D) Fourier Transform (FT) Analysis to Evaluate a High-Performance Transmission Electron Microscope (TEM)?. Microscopy and Microanalysis, 2016, 22, 971-980. | 0.4 | 3 |
| 27 | Video-rate electron-holographic interference microscopy using a liquid-crystal panel. Optical Review, 1994, 1, 304-307. | 2.0 | 2 |
| 28 | New form of Transmission Cross Coefficient for High-Resolution Imaging. Proceedings Annual Meeting Electron Microscopy Society of America, 1990, 48, 60-61. | 0.0 | 2 |
| 29 | Quantitative Annular Dark-Field Imaging of Single-Layer Graphene. Microscopy and Microanalysis, 2015, 21, 1213-1214. | 0.4 | 0 |
| 30 | Why We Need to Use 3D Fourier Transform Analysis to Evaluate a High-performance TEM. Microscopy and Microanalysis, 2016, 22, 24-25. | 0.4 | 0 |
| 31 | Quantitative Annular Dark-Field Imaging at Atomic Resolution. Microscopy and Microanalysis, 2016, 22, 304-305. | 0.4 | 0 |
| 32 | Do We Need Three-Dimensional Fourier Transform Analysis to Evaluate High-Performance TEMs?. Microscopy Today, 2018, 26, 42-49. | 0.3 | 0 |
| 33 | K-4 Current Status of Crystal Structure Analysis using Scanning Transmission Electron Microscopy. Microscopy (Oxford, England), 2019, 68, i22-i22. | 1.5 | 0 |
| 34 | Image simulation in high-resolution electron microscopy. Keikinzoku/Journal of Japan Institute of Light Metals, 2013, 63, 415-424. | 0.4 | 0 |
| 35 | High-resolution tilted single-sideband holography. , 1995, , 317-327. | | 0 |